

Announcements

Reading assignments (by lecture 3), no need to turn in anything:

Section 19.1, *Sinusoidal analysis of resonant converters*

Section 19.2, *Examples*

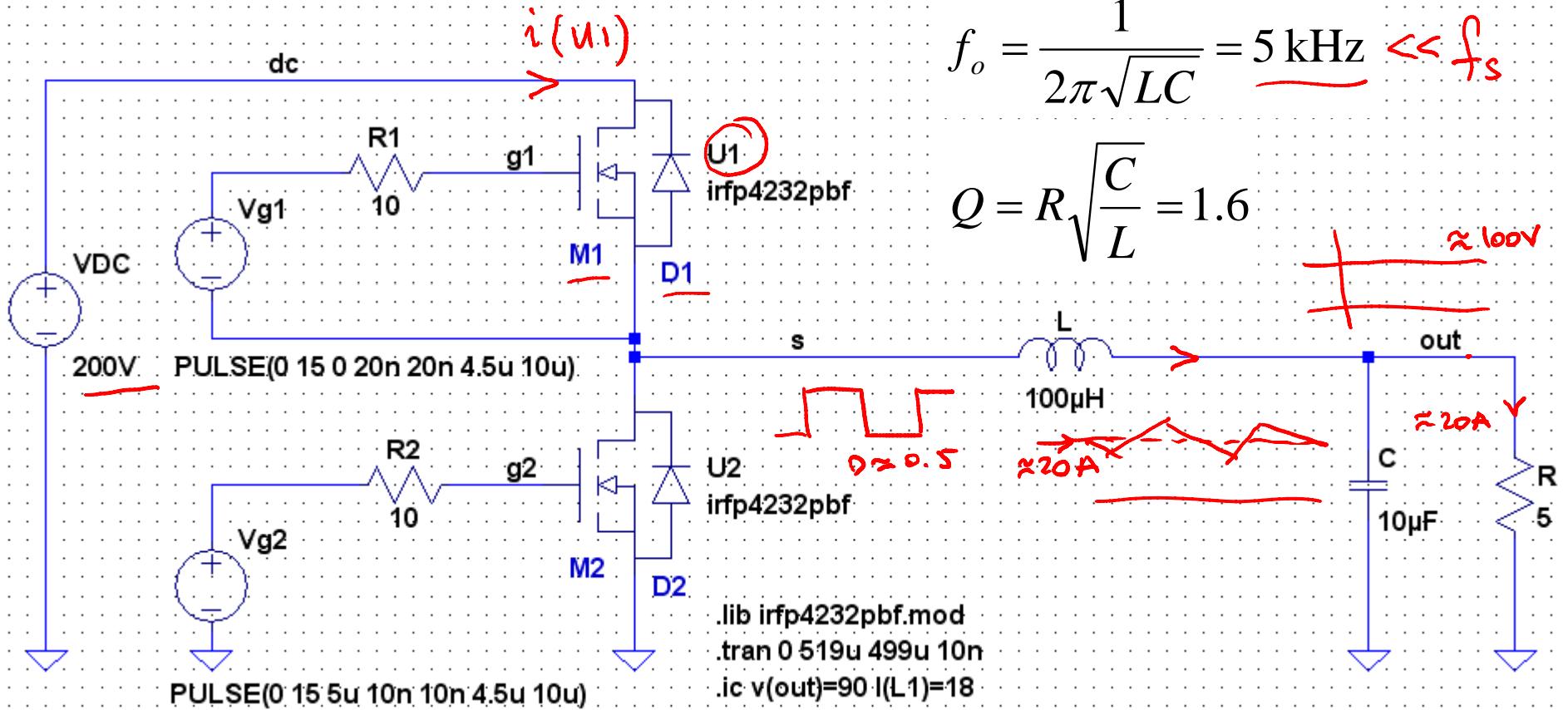
HW1 (review problems) has been posted, due Friday, Jan.22

Circuit Example: Standard “Hard-Switched” PWM Operation

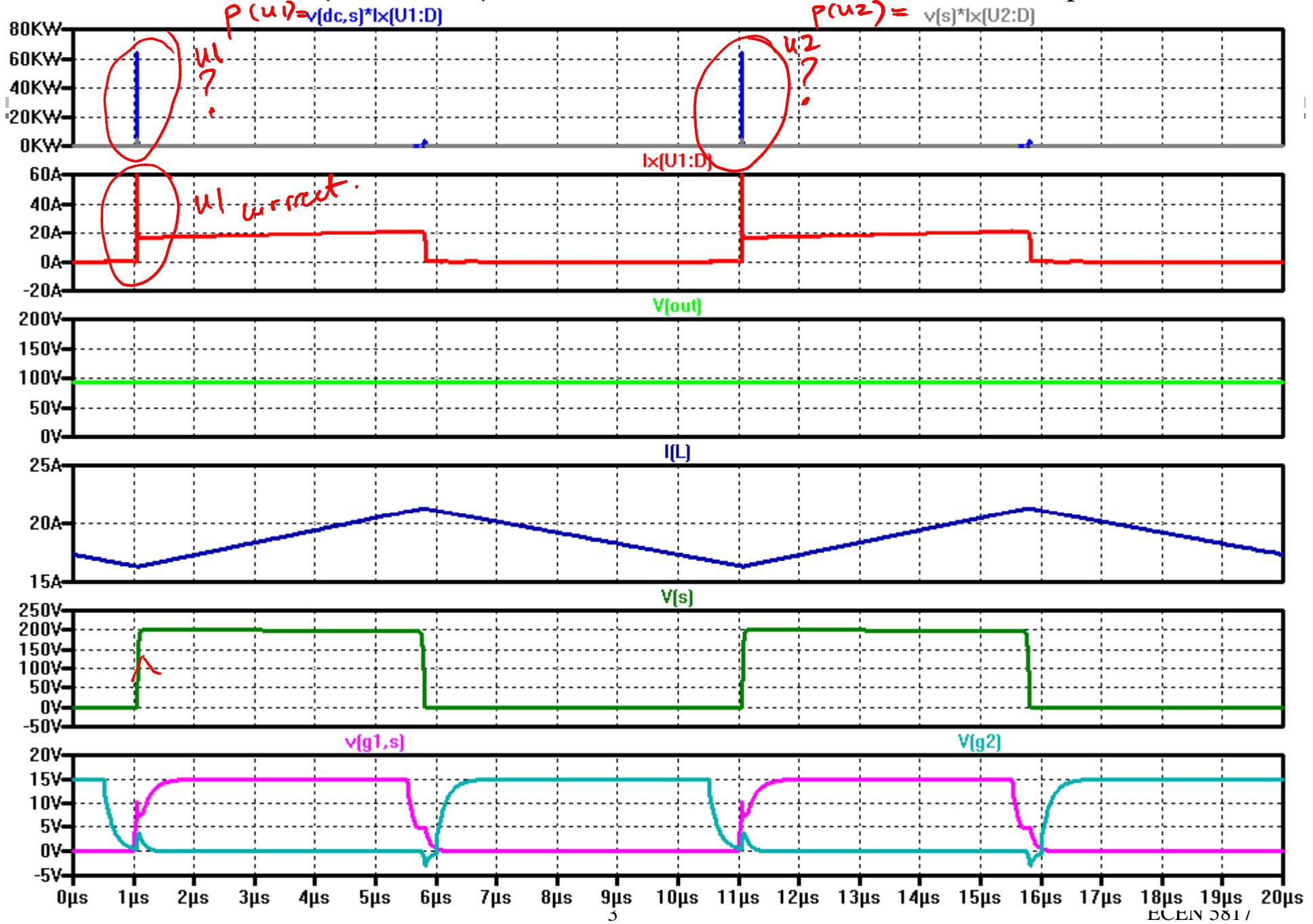
$$f_s = \underline{100 \text{ kHz}}, D \approx 0.5$$

$$f_o = \frac{1}{2\pi\sqrt{LC}} = 5 \text{ kHz} \quad \leftarrow f_s$$

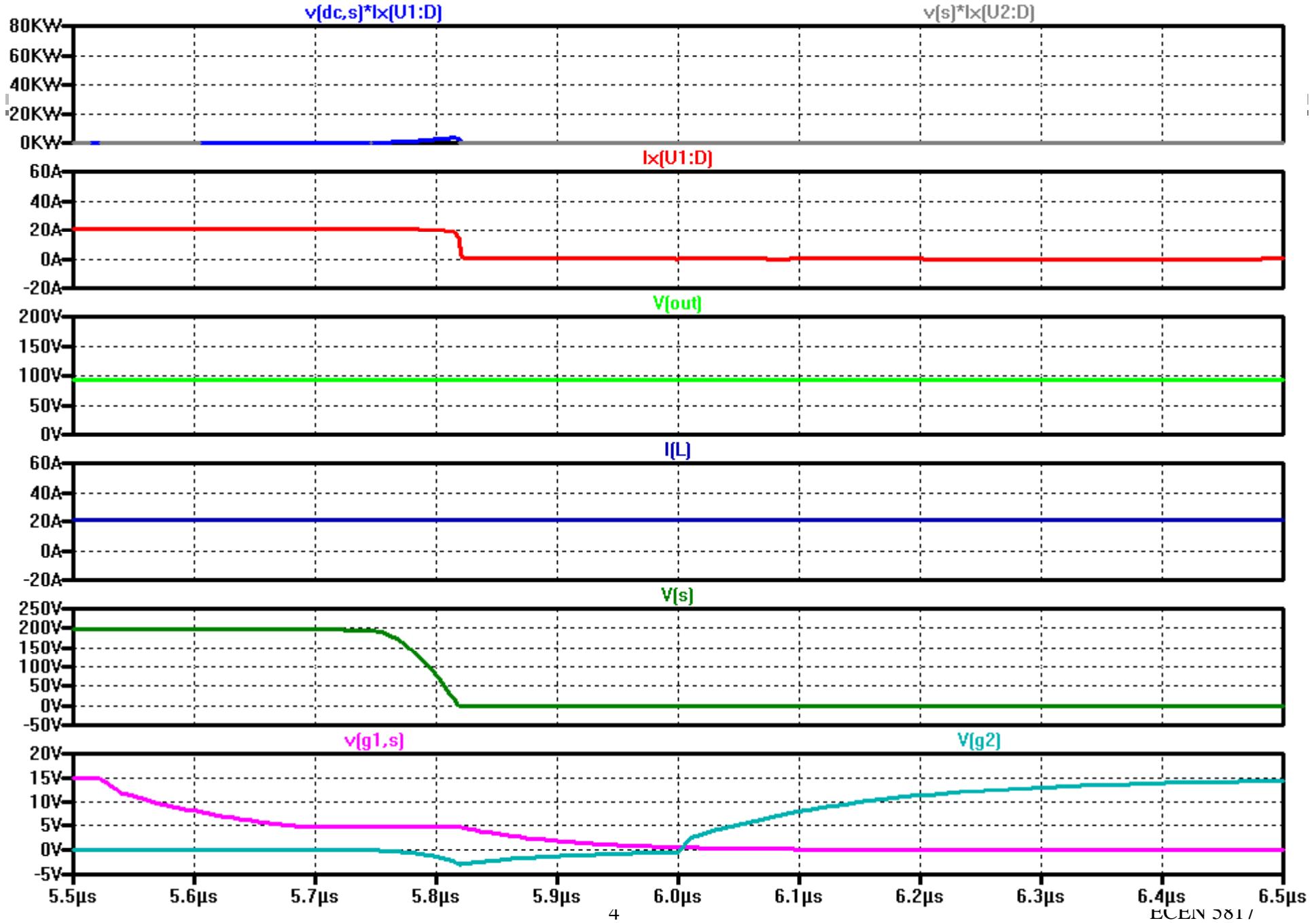
$$Q = R\sqrt{\frac{C}{L}} = 1.6$$



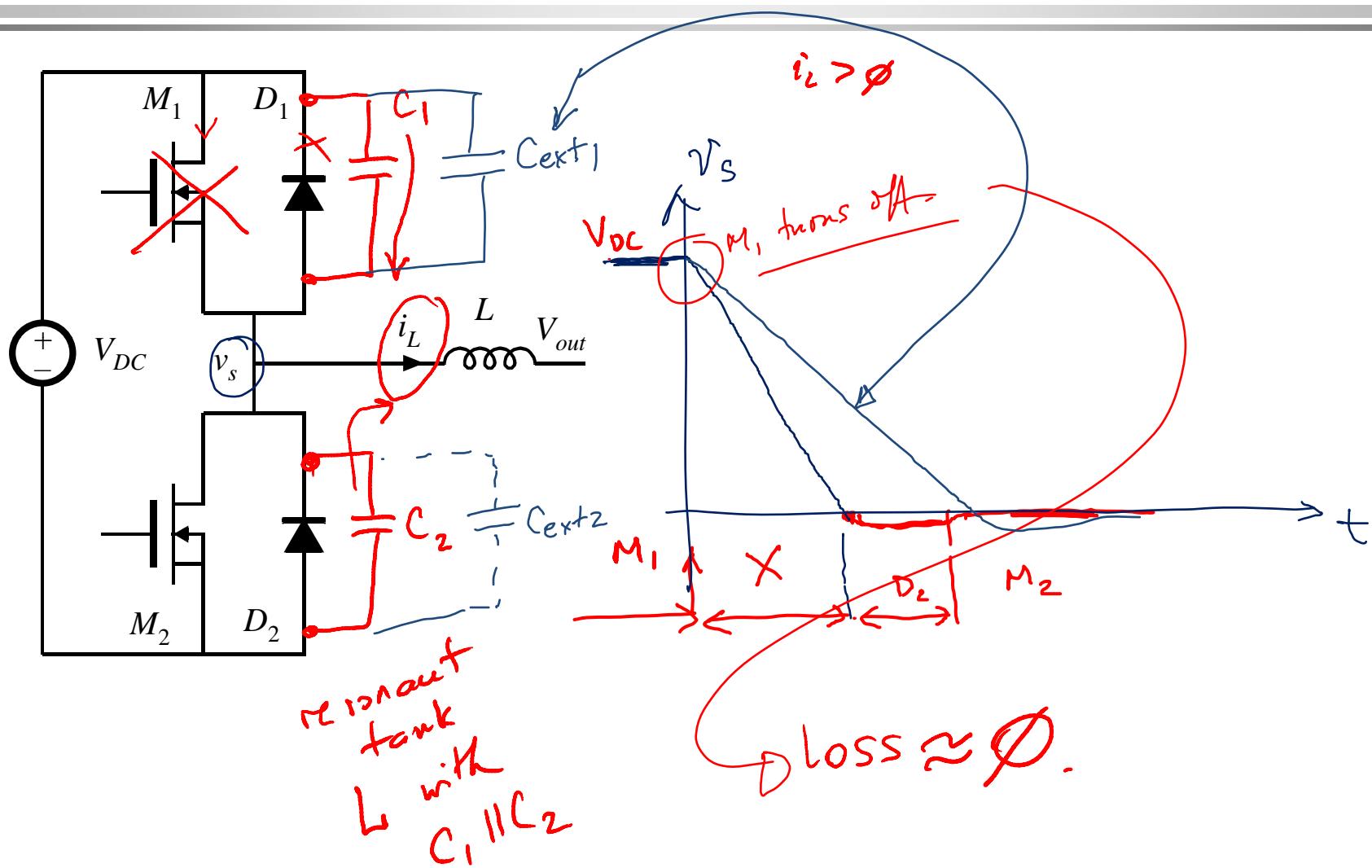
$L = 100 \mu\text{H}$, $C = 10 \mu\text{F}$, $R = 5 \Omega$: standard hard-switched PWM operation



$L = 100 \mu\text{H}$, $C = 10 \mu\text{F}$, $R = 5 \Omega$: M1 turn-off, M2 turn on transition

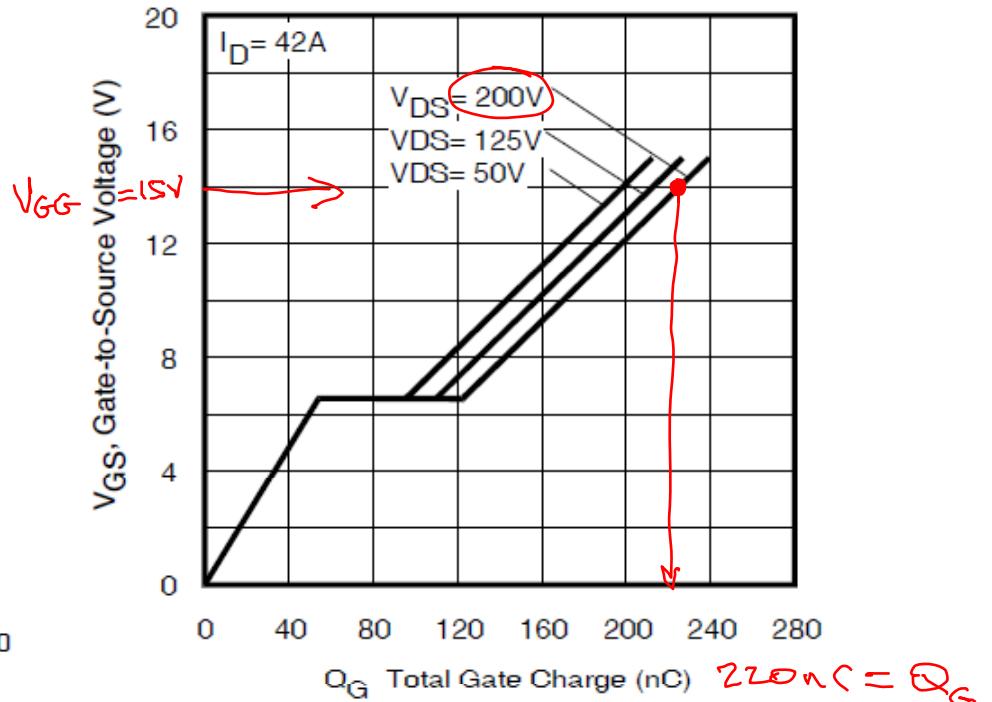
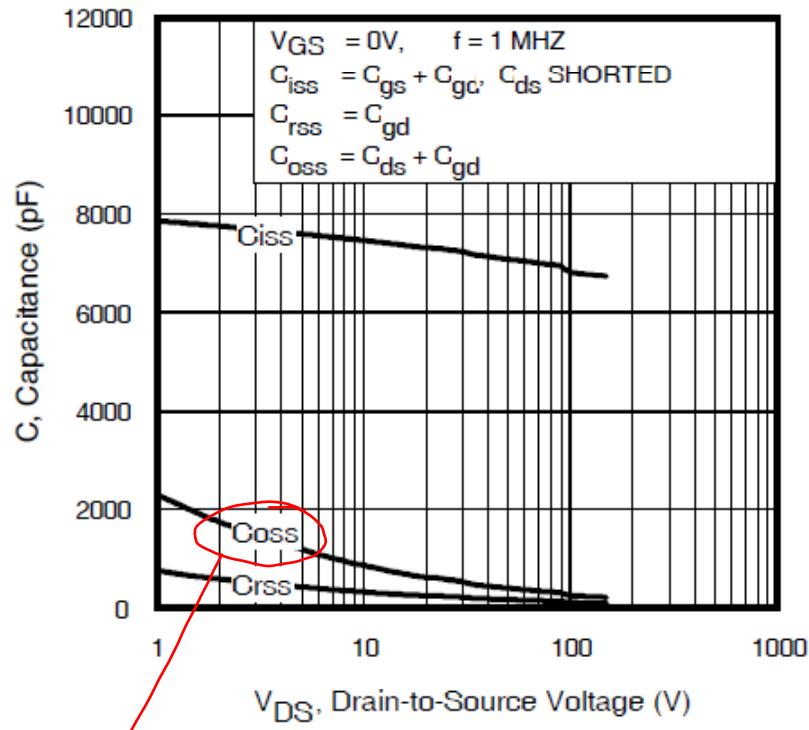


M1 turn-off, M2 turn-on transition



Device capacitances

irfp4232 example



gate-drive loss

$$Q_G \cdot V_{GS} \cdot f_S = \text{sw. loss}$$

$$220nC \cdot 15V \cdot 100kHz \approx 0.4W$$

Transistor switching times

MOSFET

- Majority carrier device
- Turn-on and turn-off delays as well as current rise/fall times are in the order of several tens of nanoseconds
- At turn off, device output capacitance slows down v_{ds} voltage increase
- No significant energy loss during MOSFET turn-off transition, even if current prior to turn-off is not zero; device capacitance is charged up

IGBT



- Conduction through built in bipolar transistor, a minority-carrier device; base charge must be removed at turn-off (“current tail” observed at turn-off)
- Turn-on/turn-off times in the hundreds of nanoseconds
- If current prior to turn-off is not zero, energy loss during turn off can be significant

Transistor switching speed and turn-off transition: IGBT example

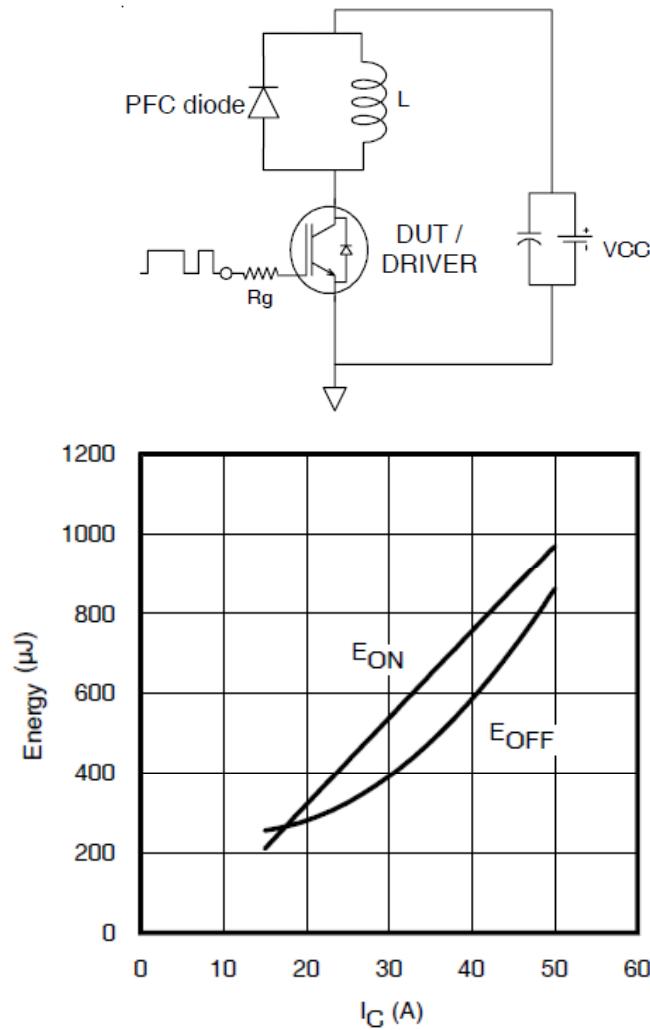
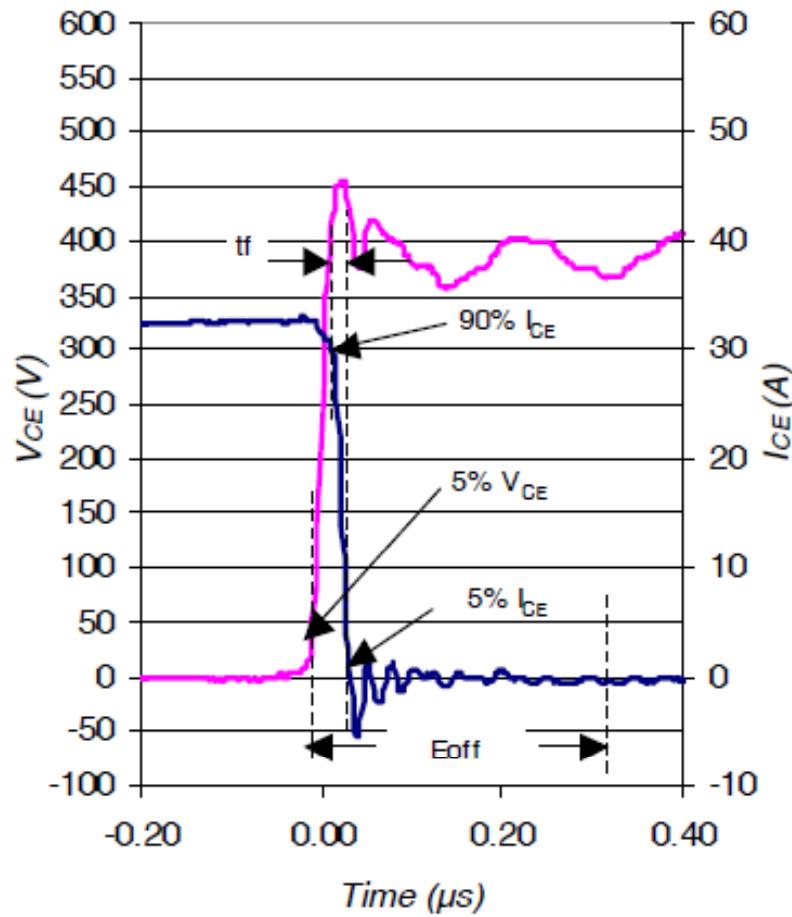
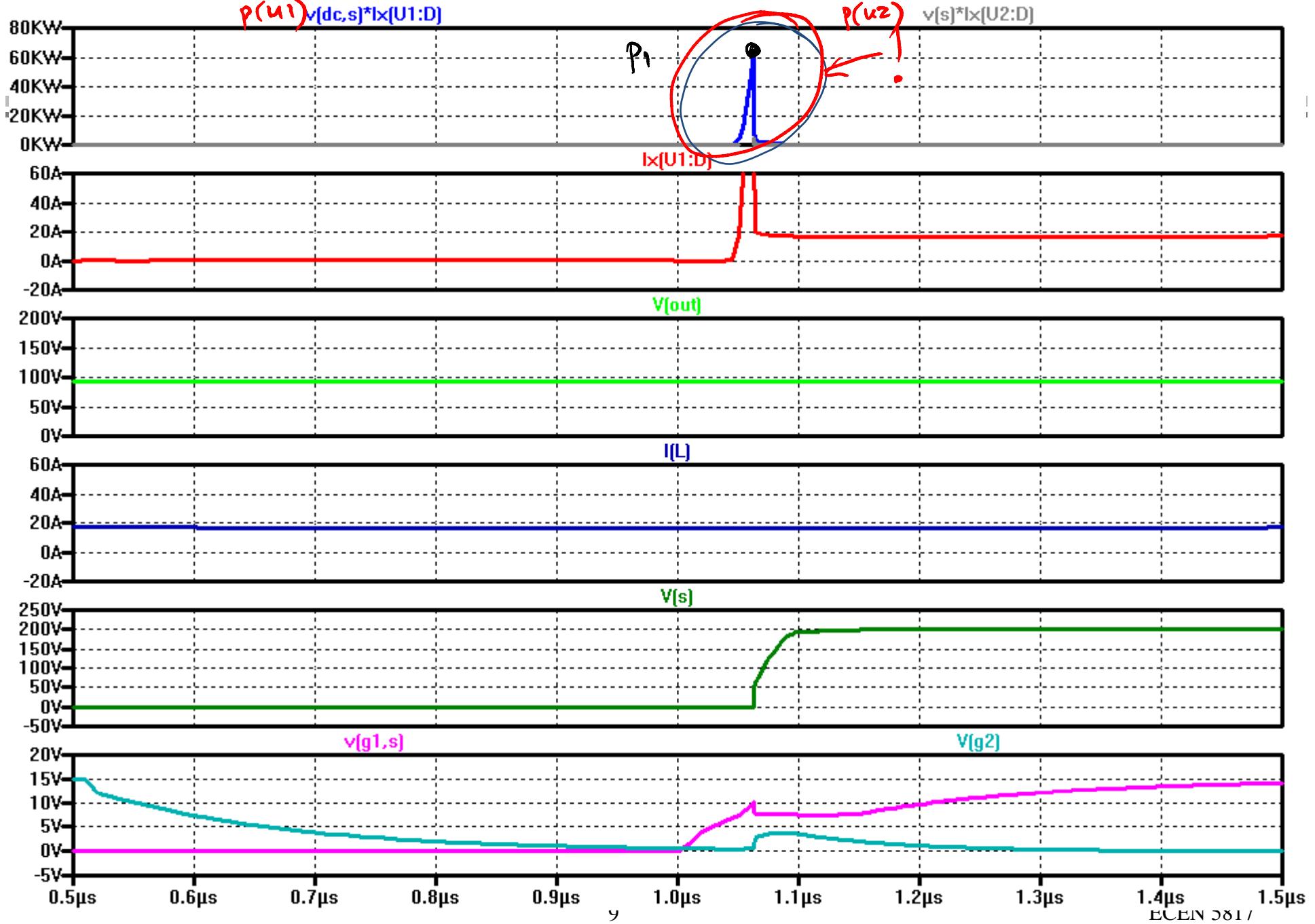


Fig. 11 - Typ. Energy Loss vs. I_C
 $T_J = 125^\circ\text{C}$; $L = 200\mu\text{H}$; $V_{CE} = 390\text{V}$; $R_G = 3.3\Omega$; $V_{GE} = 15\text{V}$.
 Diode clamp used: 30ETH06 (See C.T.3)



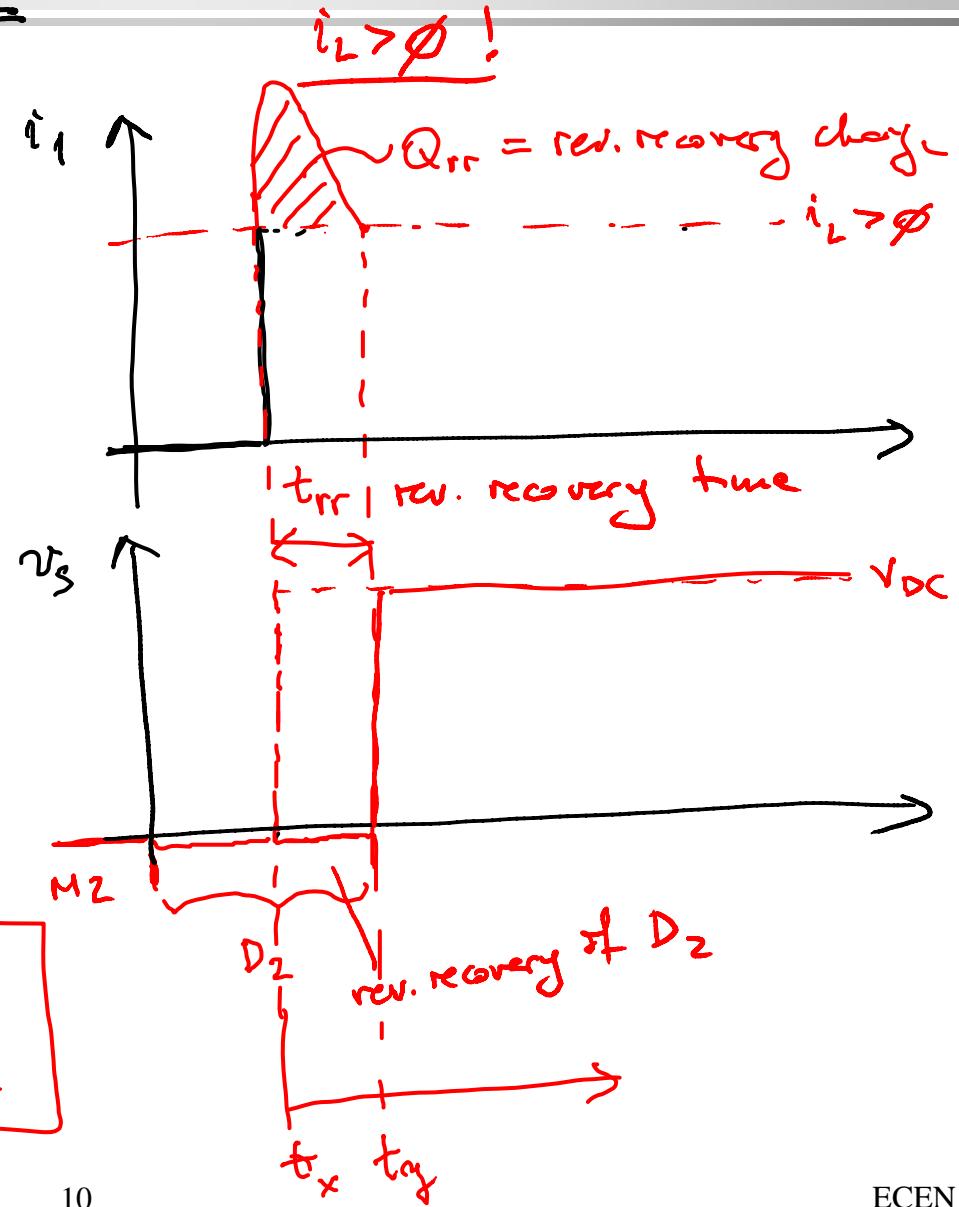
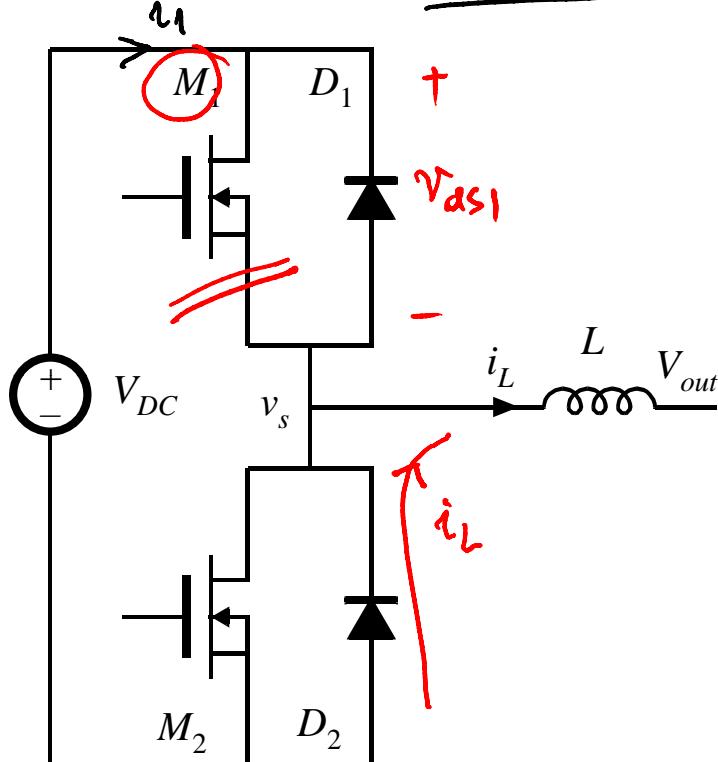
IRGP50B60 (IGBT+diode)

$L = 100 \mu\text{H}$, $C = 10 \mu\text{F}$, $R = 5 \Omega$: M2 turn off, M1 turn on transition



Hard-switched: M2 turn-off, M1 turn-on transition

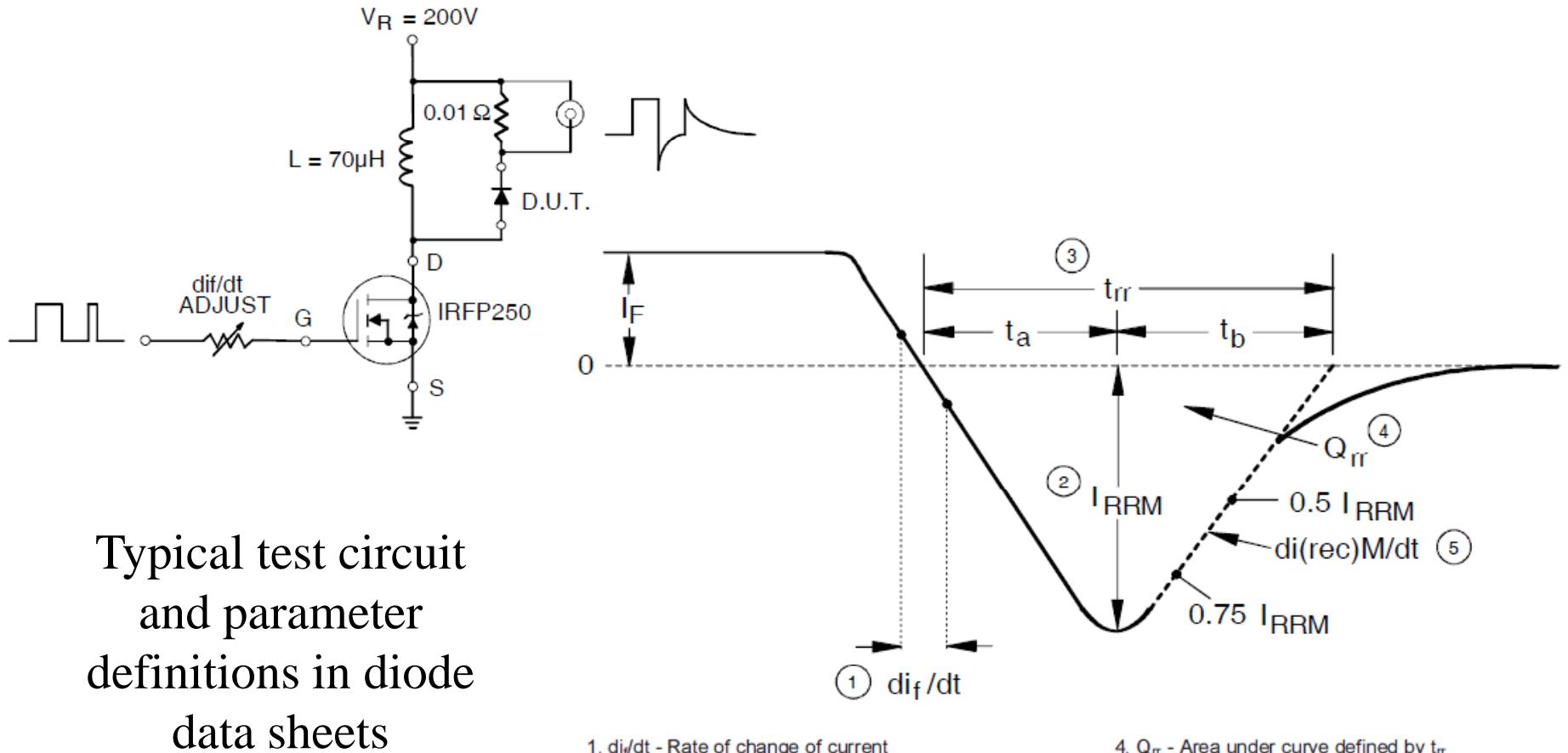
$$P_{on} = E_{on} \cdot f_s$$



$$P_1 = i_1 v_{DS1} = t_1 (V_{DC} - v_s)$$

$$E_{on} = \int_{t_x}^{t_y} P_1 dt = \boxed{i_2 \cdot t_{rr} \cdot V_{DC} + Q_{rr} \cdot V_{DC}}$$

Diode Stored Charge and Reverse Recovery



Typical test circuit
and parameter
definitions in diode
data sheets

1. di_f/dt - Rate of change of current through zero crossing
2. I_{RRM} - Peak reverse recovery current
3. t_{rr} - Reverse recovery time measured from zero crossing point of negative going I_f to point where a line passing through $0.75 I_{RRM}$ and $0.50 I_{RRM}$ extrapolated to zero current

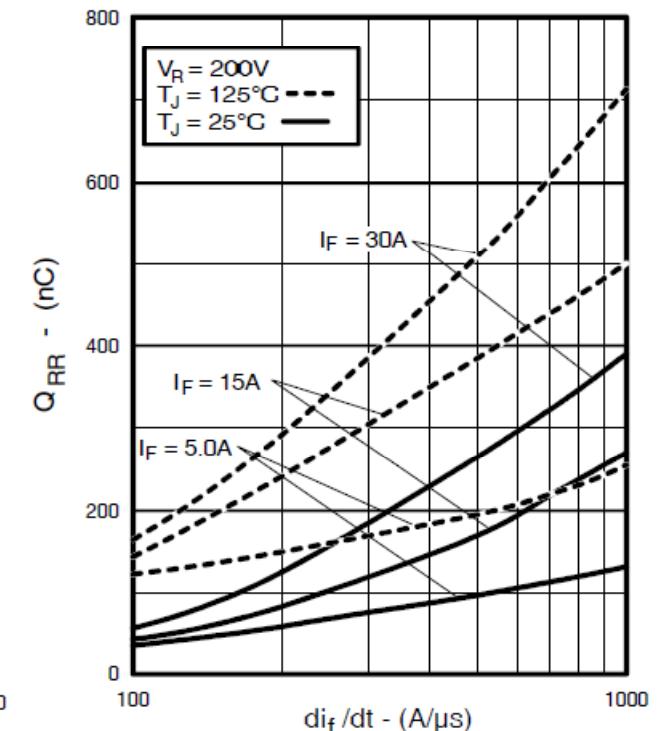
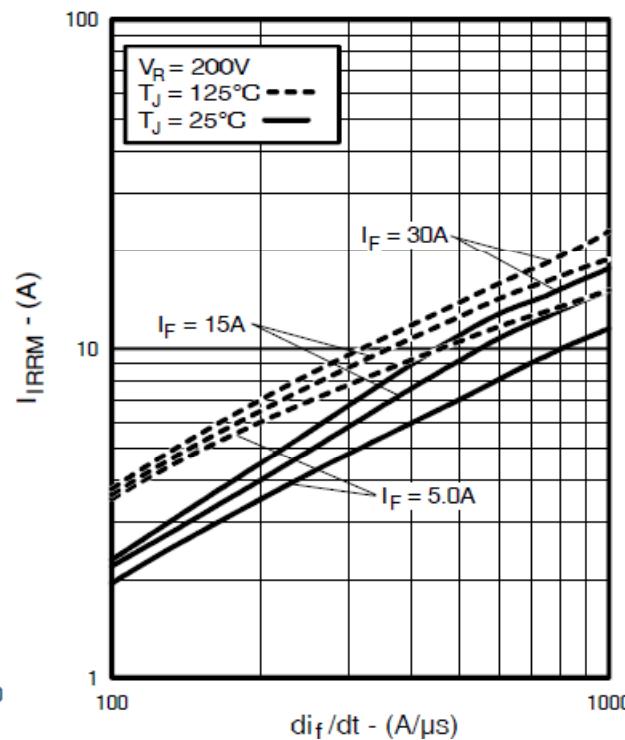
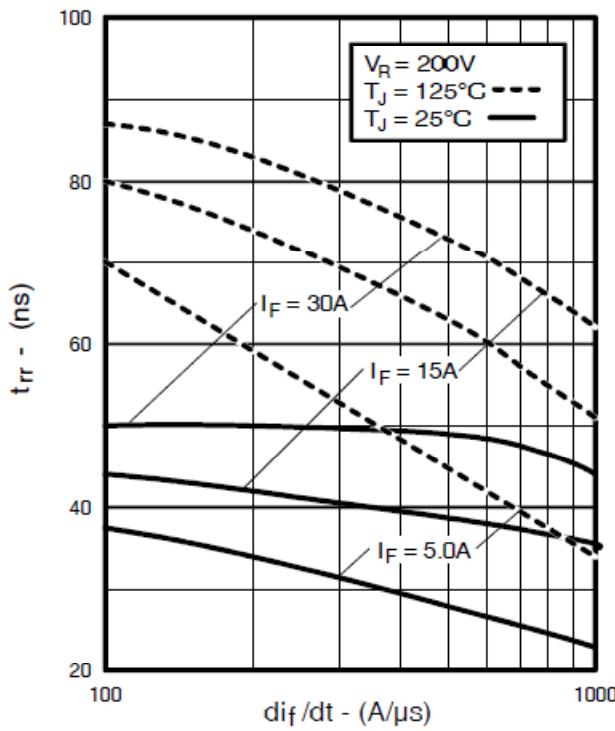
4. Q_{rr} - Area under curve defined by t_{rr} and I_{RRM}

$$Q_{rr} = \frac{t_{rr} \times I_{RRM}}{2}$$

5. $di_{(rec)}M/dt$ - Peak rate of change of current during t_b portion of t_{rr}

Example

Diode in IRGP50B60 (IGBT+diode): ultra-fast, “soft recovery”



Reverse recovery time t_{rr} , maximum reverse recovery current I_{RRM} , and reverse recovery charge Q_{rr} depend on diode forward current I_F prior to turn off, rate of current decay di_f/dt , and junction temperature T_J

Circuit Example: Introduction to Soft Switching

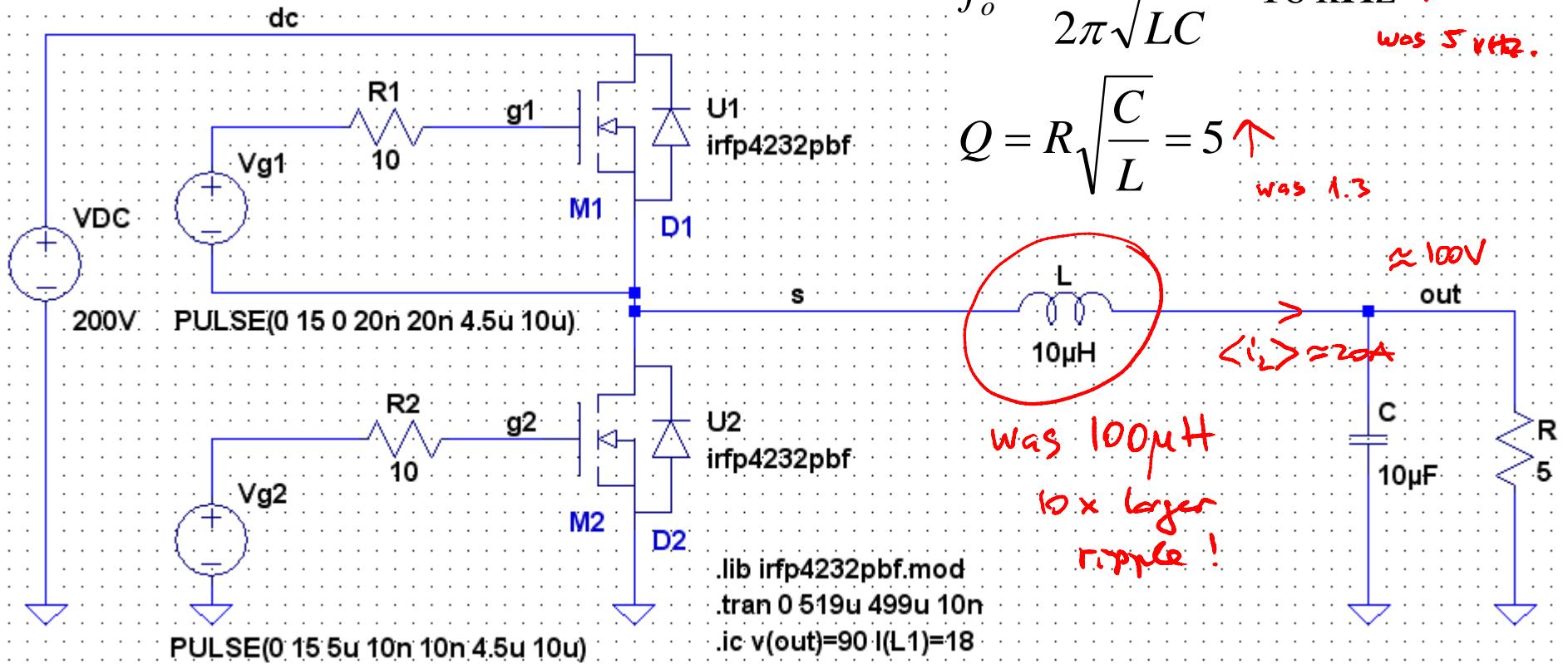
$$f_s = 100 \text{ kHz}, D \approx 0.5$$

$$f_o = \frac{1}{2\pi\sqrt{LC}} = 16 \text{ kHz}$$

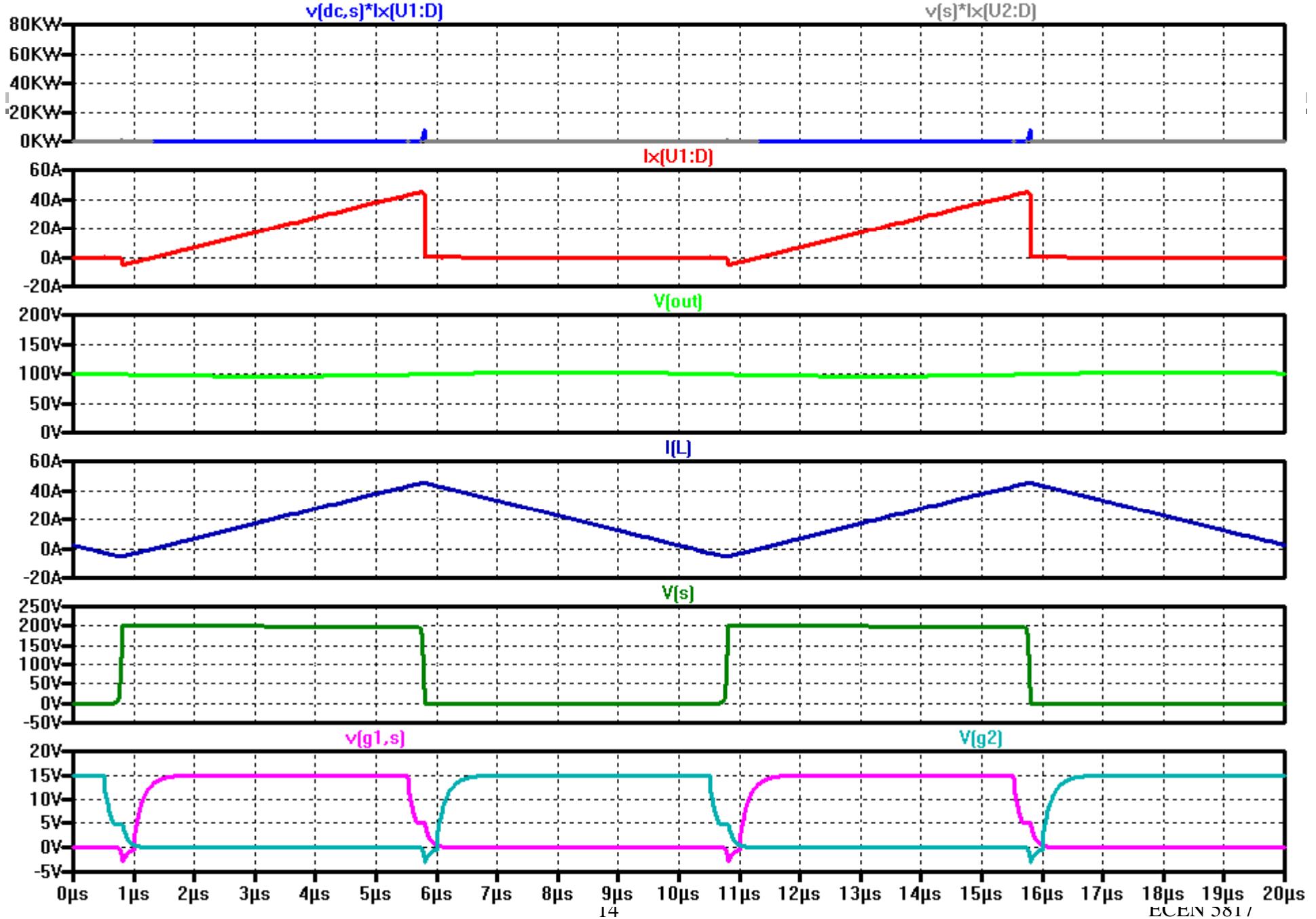
↑
was 5 kHz.

$$Q = R \sqrt{\frac{C}{L}} = 5$$

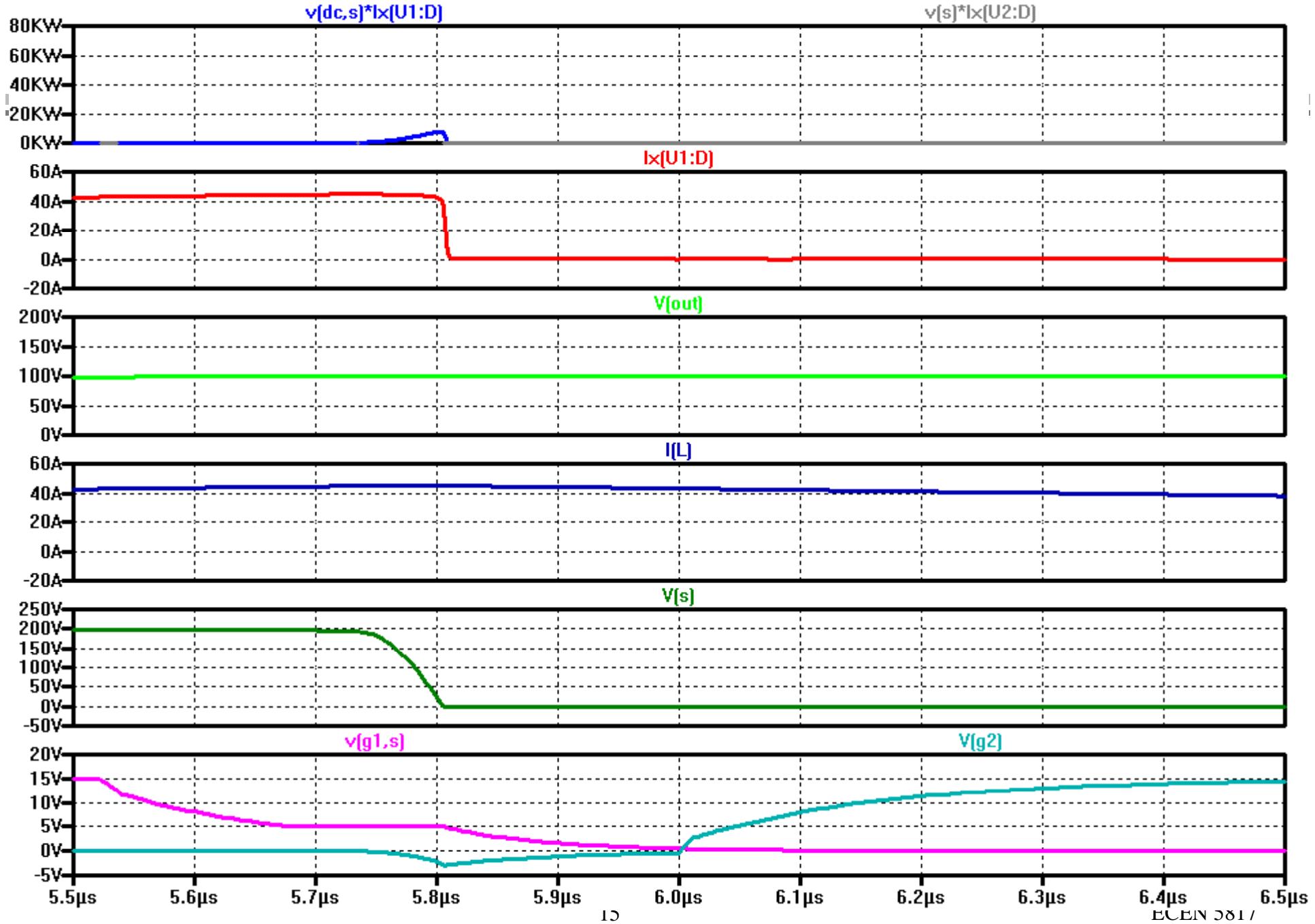
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was 1.3



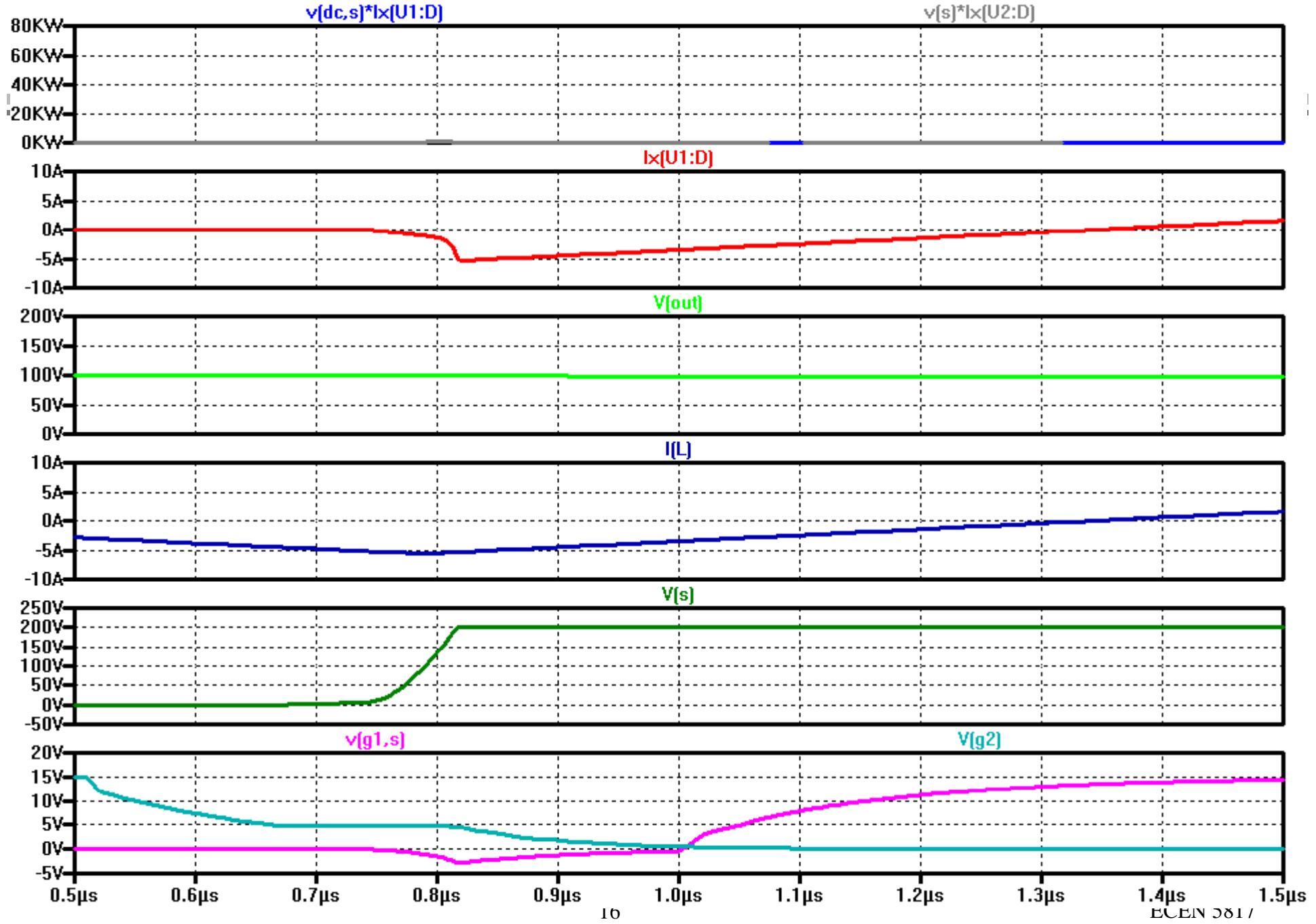
$L = 10 \mu\text{H}$, $C = 10 \mu\text{F}$, $R = 5 \Omega$: Zero-Voltage Switching (ZVS) Quasi-Square-Wave Operation



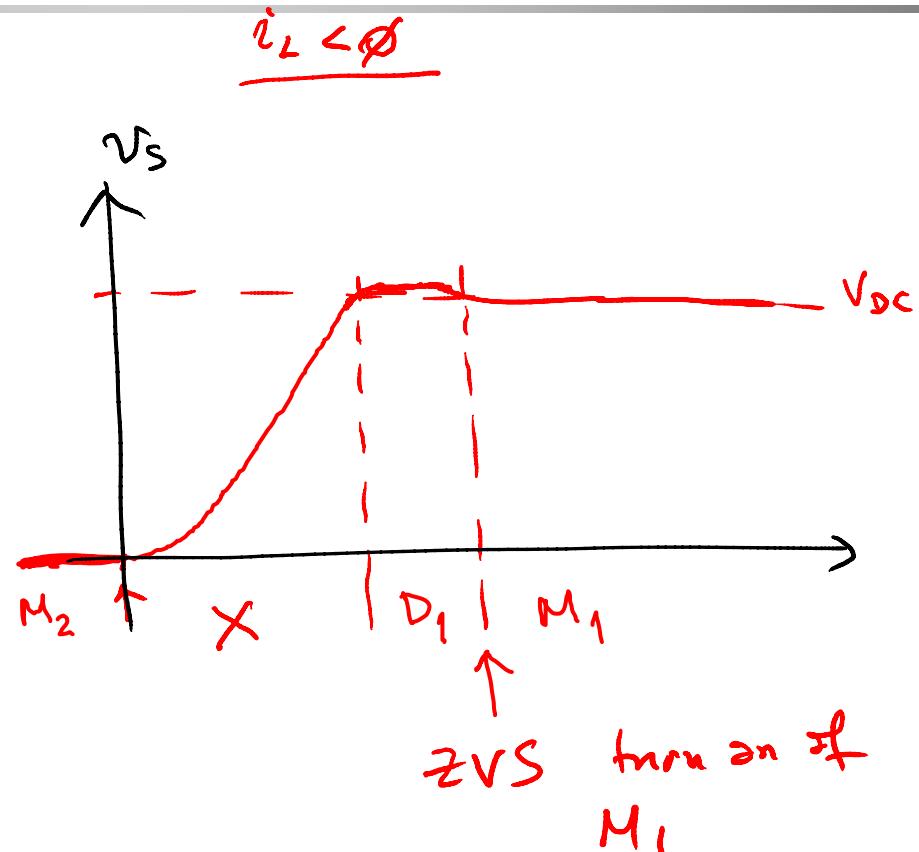
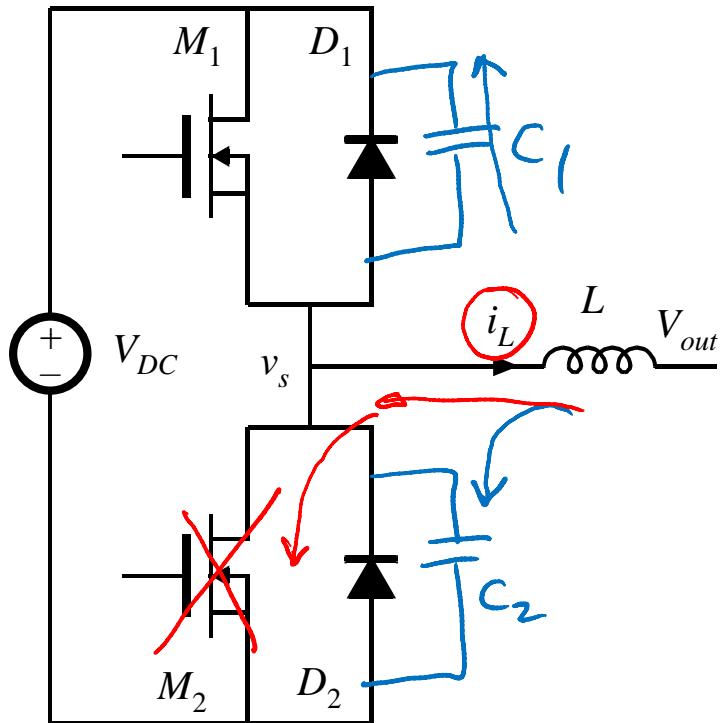
$L = 10 \mu\text{H}$, $C = 10 \mu\text{F}$, $R = 5 \Omega$: ZVS-QSW M1 turn-off, M2 turn-on



$L = 10 \mu\text{H}$, $C = 10 \mu\text{F}$, $R = 5 \Omega$: ZVS-QSW M2 turn-off, M1 turn on



ZVS-QSW: M2 turn-off, M1 turn-on transition



Energy loss $\approx \phi$